

Thick800A

X-Ray Fluorescence Spectrometer

*Precision Instruments
by Skyray*



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SKYRAY INSTRUMENT

Product Introduction

The instrument is specially designed for plating thickness measurement, rapid and non-destructive analysis for elements and contents of plating. The characteristics are as the following:

- ◆ Top lightening
- ◆ Up & down sample platform
- ◆ Movable platform with high accuracy
- ◆ Micro collimator
- ◆ Detector with high resolution
- ◆ Visual operation
- ◆ Auto height positioning
- ◆ Auto spot search
- ◆ Mouse positions the test point
- ◆ Excellent ray shielding
- ◆ Super large chamber design
- ◆ Safe protection of test interface



Technical Specifications

Detection range for plating: 25 elements such as
 Cr \ Fe \ Ni \ Cu \ Zn \ Au \ Ag \ Pt \ Pd
 Plating layers: 3 layers
 Stability: 0.005~0.01 μm ; RSD: 0.1%
 Arbitrary optional analysis and identification models
 Independent matrix effect correction models

Multi-variable non-linear regression procedure
 Excellent repeatability: 0.1%
 Long-time working stability: 0.1%
 Ambient temperature: 15°C~15°C
 Power supply: AC 220V \pm 5V.
 purified stabilized voltage power supply

Application Fields

- ◆ Detection for plating thickness of metals, content of plating solution and plating.
- ◆ Detection for golden, platinum, silver, other precious metals and various jewelries content.
- ◆ Mainly applied in precious metal and jewelry processing industries; bank, jewelry selling and detection institution, electroplating industries.



Main performances

- ◆ Top-lightening: Meet the requirement for testing samples of different thicknesses and irregular shapes.
- ◆ Micro collimator: 0.1X1.0; can be used in testing micro point so as to improve testing accuracy.
- ◆ Movable platform with high accuracy: Repeated location accuracy is less than 0.005mm and the test point can be precisely located.
- ◆ Height laser: Auto height positioning ensures the testing for irregular samples, meanwhile protects the up & down platform.
- ◆ Auto spot search: Precisely locates spot to make sure the test point is aligned to the spot.
- ◆ Arbitrary measurement with mouse: Mouse can control the movable platform; it is able to click the test point by mouse.
- ◆ Detector with high resolution: Improve analysis accuracy.
- ◆ Safety: Excellent ray shielding; the test interface is protected by high sensitivity sensor.

Configuration

- ◆ Open sample chamber
- ◆ Double-laser locating device
- ◆ Lead glass shield cover.
- ◆ Si-Pin detector
- ◆ Detect electronic circuit by signal.
- ◆ Precise 2-D movable sample platform. The detection system can lift up and down to realize 3-D movement.
- ◆ High and low voltage power supply
- ◆ X-ray tube
- ◆ Altitude transducer
- ◆ Protection transducer
- ◆ Computer and ink jet printer

